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(12) **United States Design Patent**
Ming et al.

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(45) **Date of Patent:** **** Apr. 3, 2001**

(54) **FORK PROBE THERMOMETER**

4,332,409 * 6/1982 Stachowicz 294/55.5 X

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* cited by examiner

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(57) **CLAIM**

The ornamental design for a fork probe thermometer, as
shown.

(**) Term: **14 Years**

DESCRIPTION

(21) Appl. No.: **29/123,934**

FIG. 1 is a perspective view of a the fork probe thermometer
showing our new design;

(22) Filed: **May 26, 2000**

FIG. 2 is a right side elevation view of the fork probe
thermometer shown in FIG. 1, the left side elevation view
being a mirror image thereof;

(51) **LOC (7) Cl.** **07-02**

(52) **U.S. Cl.** **D7/683; D10/57**

(58) **Field of Search** D7/653, 683; D10/53,
D10/57; 30/129, 147, 148, 142, 150, 322,
323; 294/55.5, 61; 374/141, 155, 184, 208-210

FIG. 3 is a front elevation view of the fork probe thermom-
eter of FIG. 1;

FIG. 4 is a top plan view of the fork probe thermometer
shown in FIG. 1;

(56) **References Cited**

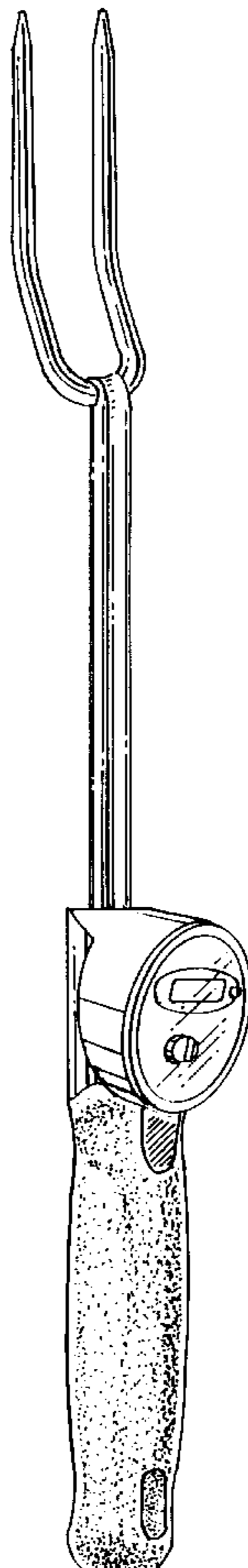
U.S. PATENT DOCUMENTS

- D. 227,294 * 6/1973 Maynard D7/643 X
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- 3,552,210 * 1/1971 Wright, Jr. 374/155

FIG. 5 is a bottom plan view of the fork probe thermometer
shown in FIG. 1; and,

FIG. 6 is a back plan view of the fork probe thermometer
shown in FIG. 1.

1 Claim, 2 Drawing Sheets



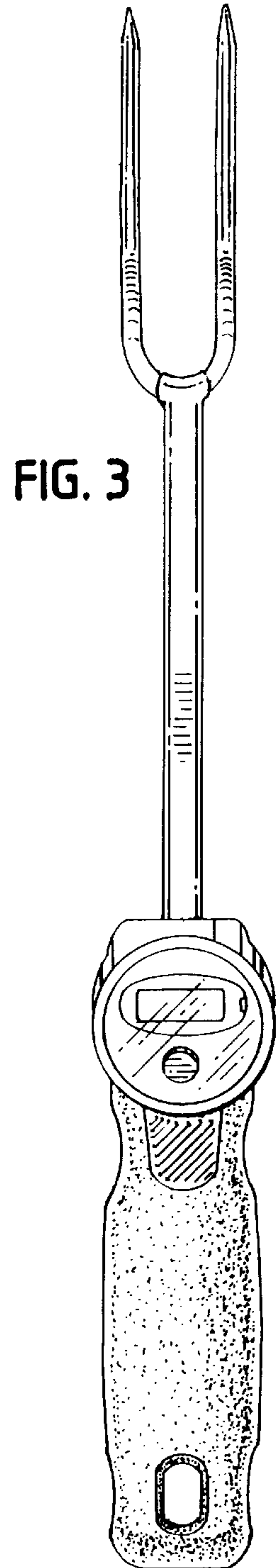
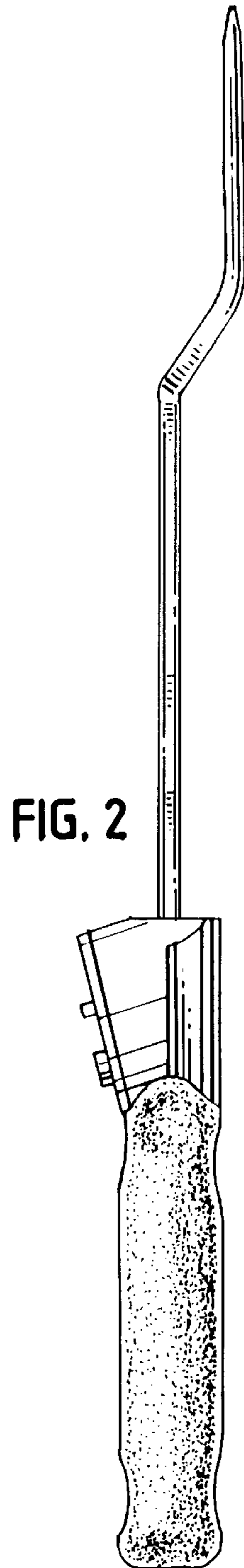
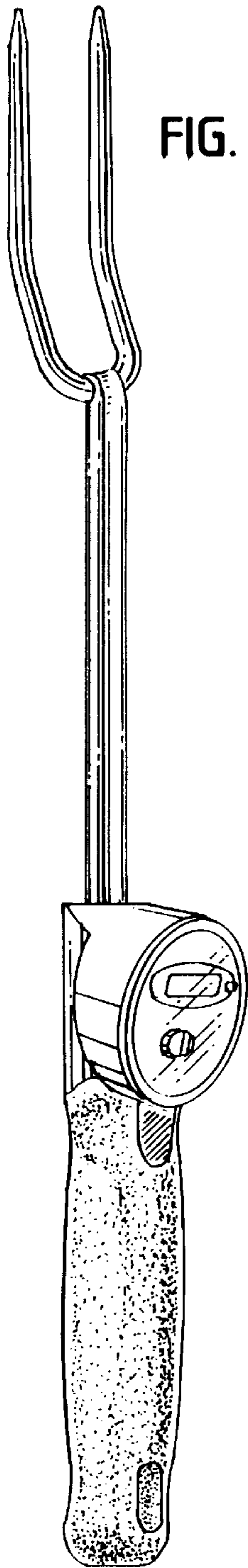


FIG. 4

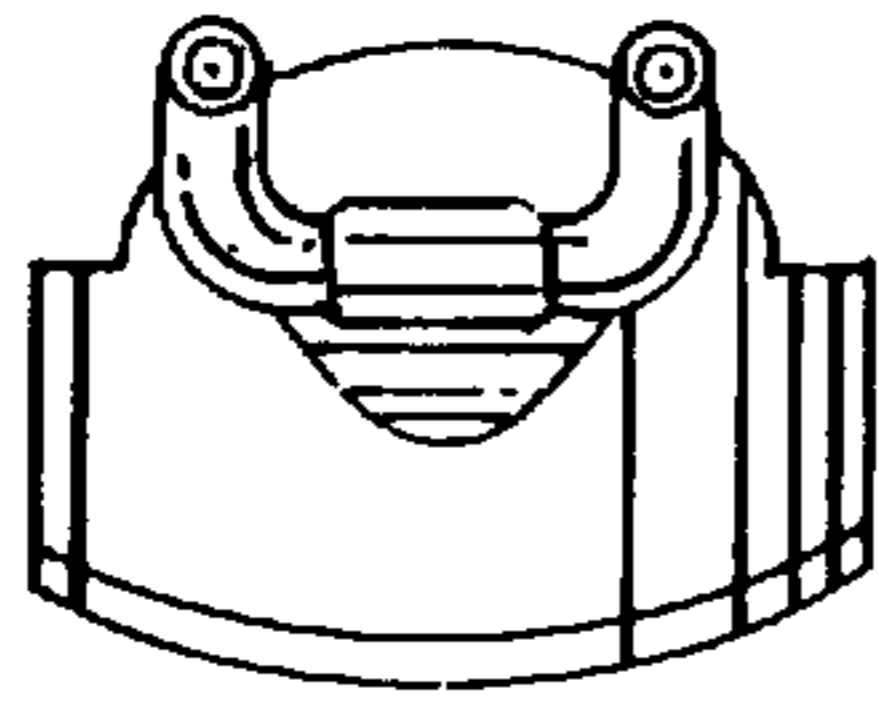


FIG. 5

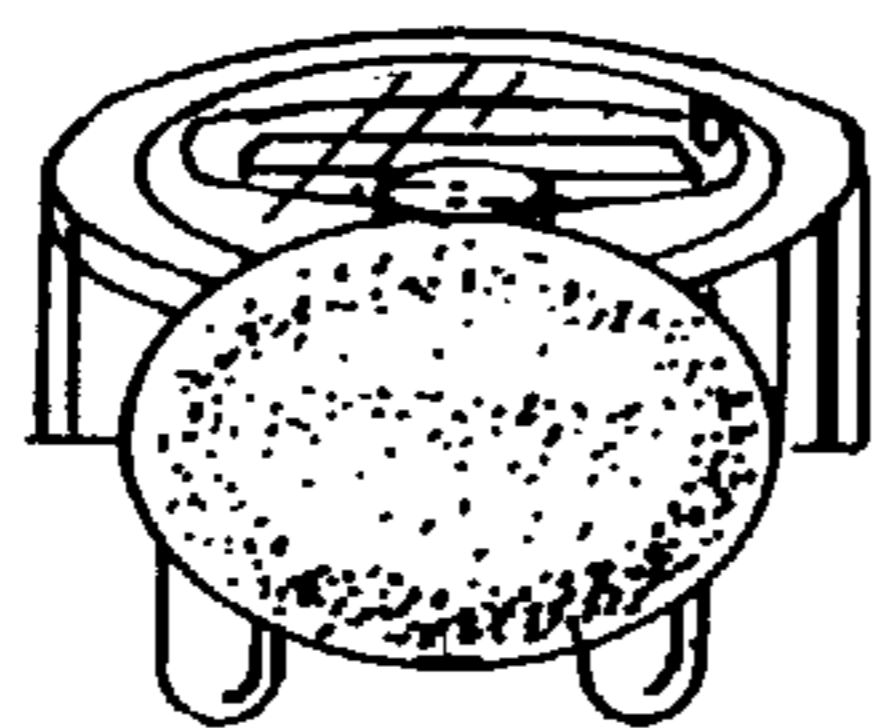


FIG. 6

